

FORM PTO-1449 (modified)
 To: U.S. Department of Commerce
 (PW FORM PAT-1449)
 Patent and Trademark Office



Atty. Dkt. No.	M#	Client Ref.
	044182	308723

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Date: October 13, 2004

Page **1** of **1**

Applicant: Kraft, Raymond H.

Appln. No.: 10/800,420

Filing Date: March 12, 2004

Examiner: Group Art Unit: 2621

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
/JWL/ AR	4,467,211	08/1984	Smith	250	492.2	05/23/83
/JWL/ BR	6,178,272	01/2001	Segman	382	298	02/02/99
CR						
DR						
ER						
FR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
					Enclosed	No
GR						
HR						
IR						
JR						

OTHER (Including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

/JWL/ KR	QI, Fei; Chengying Hua, "Efficient automated microarray image analysis" Second International Conference on Image and Graphics, SPIE Vol. 4875 (2002) pp. 567-574		
/JWL/ LR	SCHATTENBURG, M. L., C. Chen, P. N. Everett, J. Ferrera, P. Konkola, and H. I. Smith, "Sub-100 nm metrology using interferometrically produced fiducials" J. VAc. Sci. Technol. B 17(6), Nov/Dec 1999, pp. 2692-2697		
/JWL/ MR	BRANDLE, Norbert, H. Lapp, and H. Bischof, "Automatic Grid Fitting for Genetic Spot Array Images Containing Guide Spots" Lecture Notes in Computer Science, Springer Verlag, New York, NY, US, Vol. 1689, September 1999 pp. 357-366		
NR			
OR			
PR			

Examiner /John Lee/ Date Considered: 10/11/2007

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.